

Field Effect Transistor - (FET) →

① Junction FET (JFET)

② Metal oxide Semiconductor FET (MOSFET)

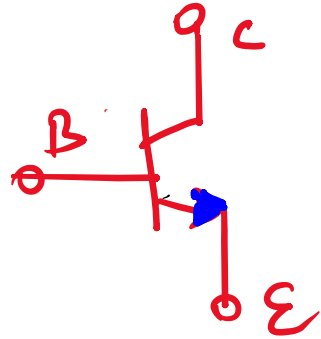
We create the channel → (i) Enhancement type MOSFET

channel is already formed → (ii) Depletion type MOSFET.

The difference between BJT & FET →

BJT

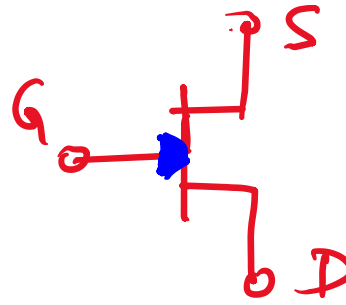
①



C - Collector
B - Base
E - Emitter

FET

①



S - Source
D - Drain
G - Gate

② npn & pnp

③ Current controlled device

④ BJT are less temperature

Stable.
⑤ Less input impedance

② n-channel or p-channel.

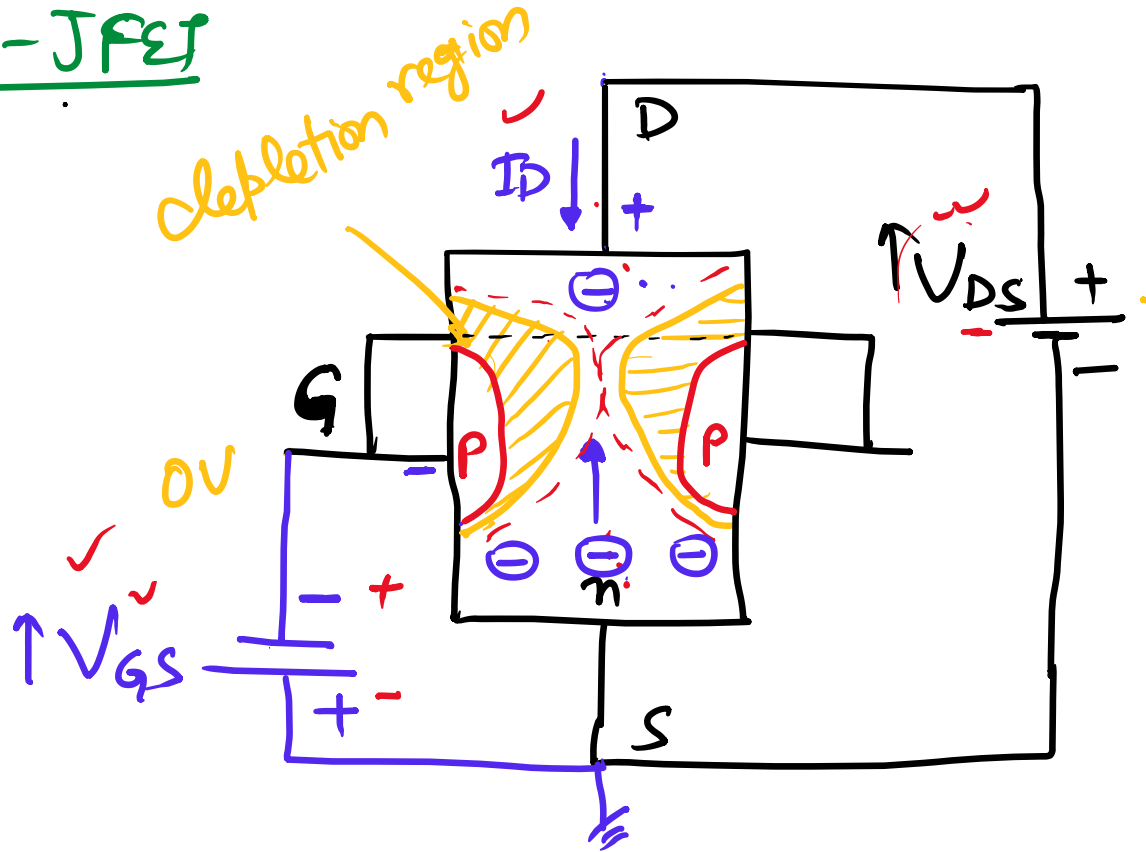
③ Voltage controlled device

④ more temperature stable

⑤ provide high input impedance.

Operation & Characteristics of JFET

n-JFET



① $V_{GS} = 0, V_{DS} \uparrow$

→ At the level of V_{DS} , at which the width of depletion region fully covers the channel region.

→ no charge carriers will be flowing from source to drain and $I_D = 0$ ($V_{DS} = V_p$)

→ This value of V_{DS} at which channel is completely closed is called "pinch off" voltage (V_p)

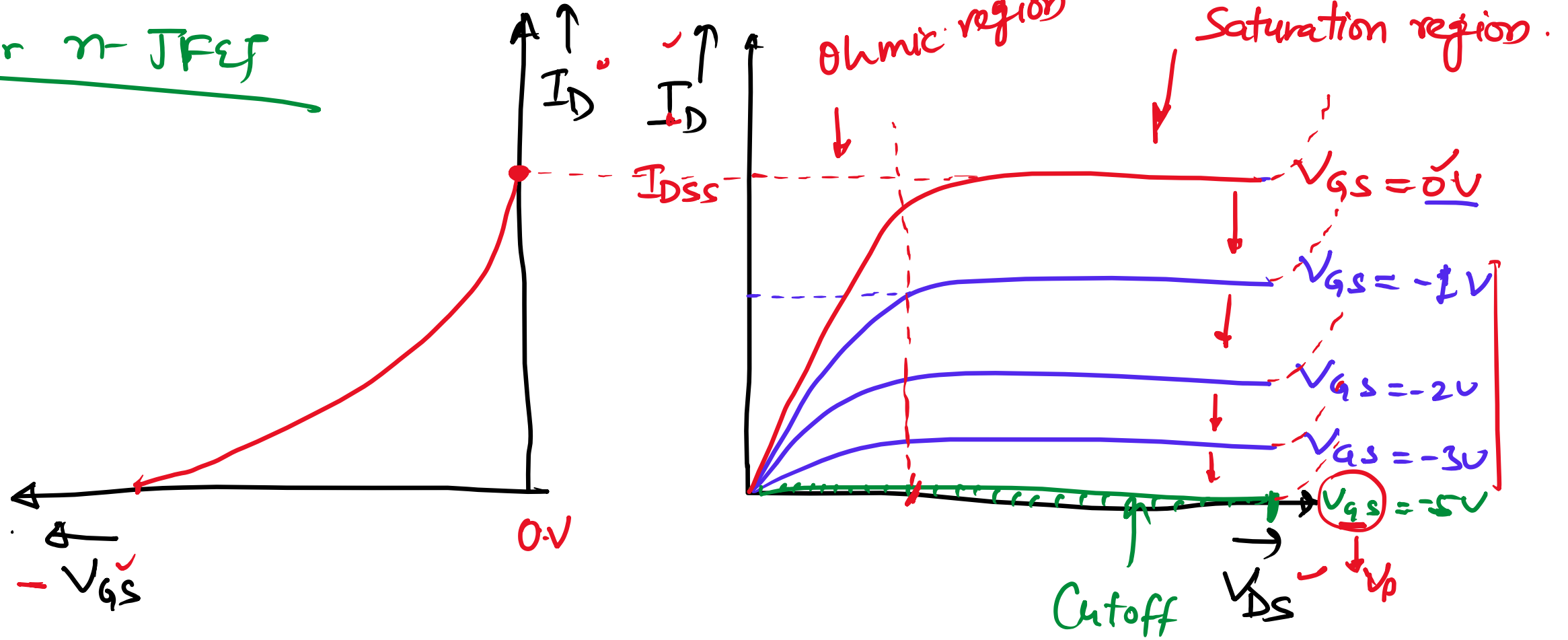
② $V_{GS} \rightarrow -V_{DS}$ (negative).

→ The applied negative V_{GS} increases the depletion width due to reverse biased pn junction. and V_{DS} attains the level of V_p at smaller values.

→ The current and number of charge carriers is being controlled by V_{GS} & V_{DS} so FET is called voltage controlled device.

Transfer characteristics of JFET

for n-JFET



→ Q. Explain the operation for p-type of JFET & also draw the transfer characteristics.

Shockley's Equation -

$$I_D = I_{DSS} \left(1 - \frac{V_{GS}}{V_P} \right)^2$$

Pinch-off voltage.

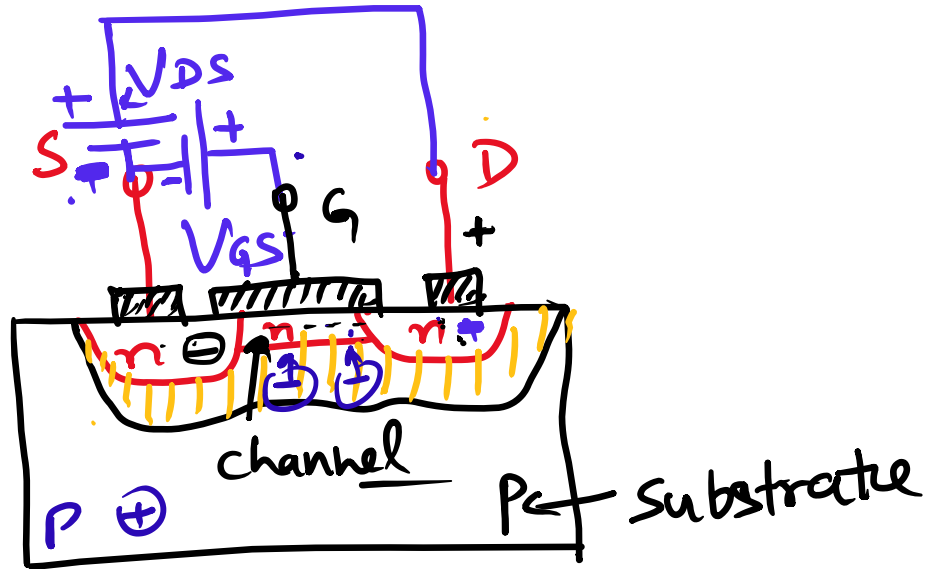
at $V_{GS} = 0V \Rightarrow I_D = I_{DSS} (1 - 0)^2 = I_{DSS}$

at $V_{GS} = V_P \Rightarrow I_D = I_{DSS} (1 - 1)^2 = 0$

* In FET's Gate is always reverse biased.

Metal oxide Semiconductor FET (MOSFET) →

① Depletion type MOSFET → P-channel
n-channel. (channel is already formed)



① $V_{GS} = 0V$, $V_{DS} \uparrow$

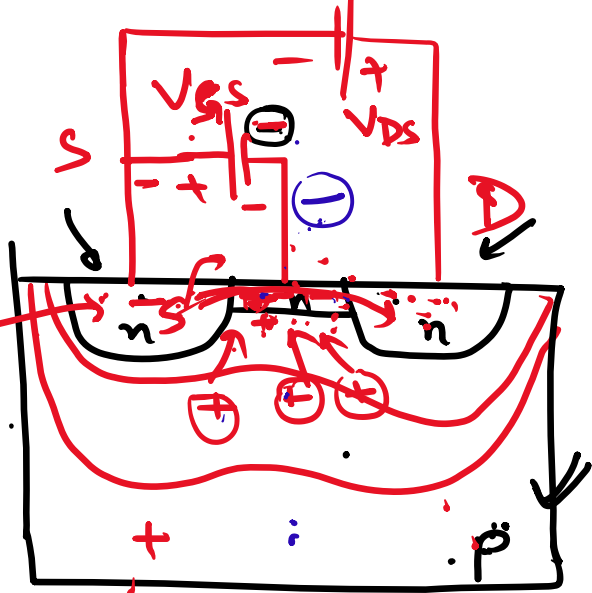
② $V_{GS} \rightarrow +ve$ ✓

→ for large value of applied

V_{GS} for which depletion layer is sufficiently large to close the channel then Pinch-off occurs.

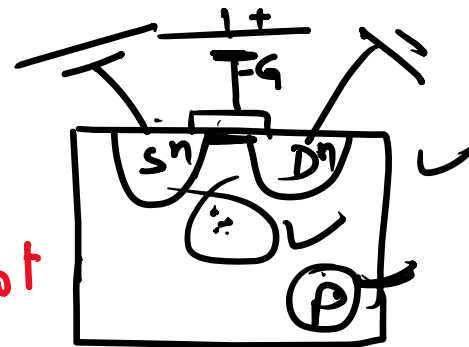
③

$V_{GS} = -ve$

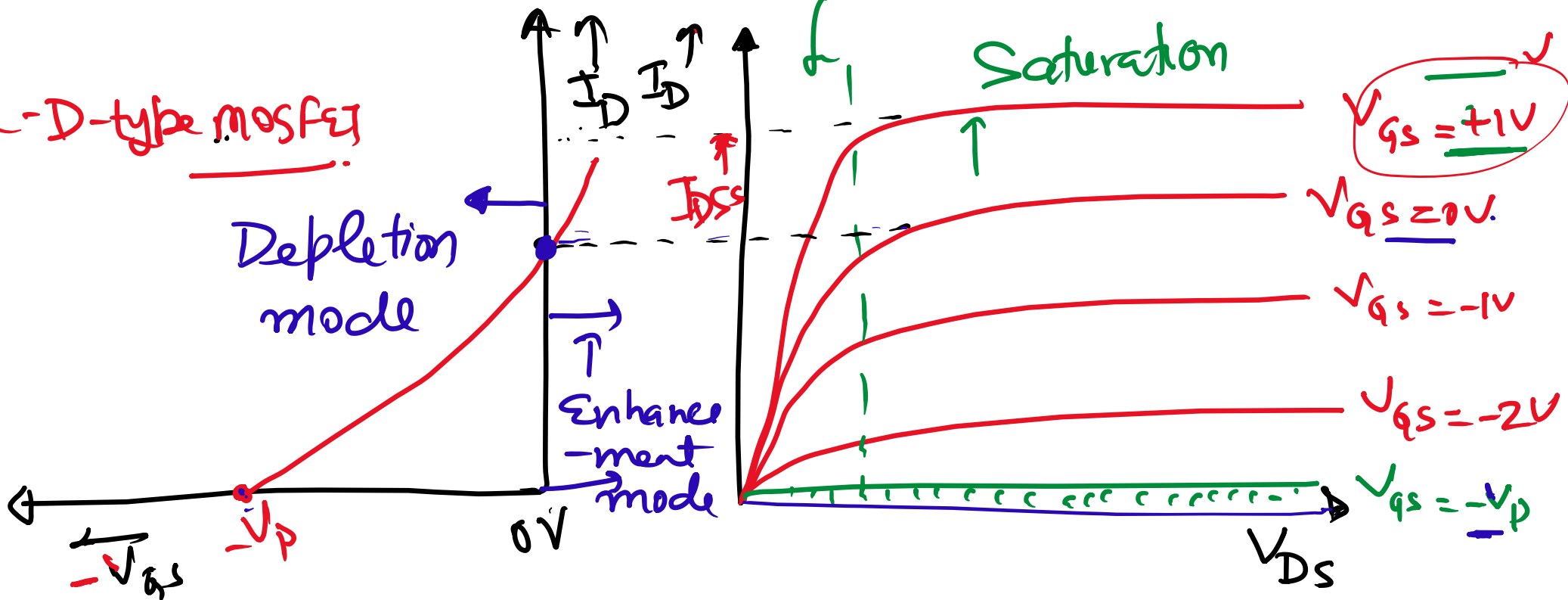


$V_{GS} = 0V$

Channel can't create charge carrier

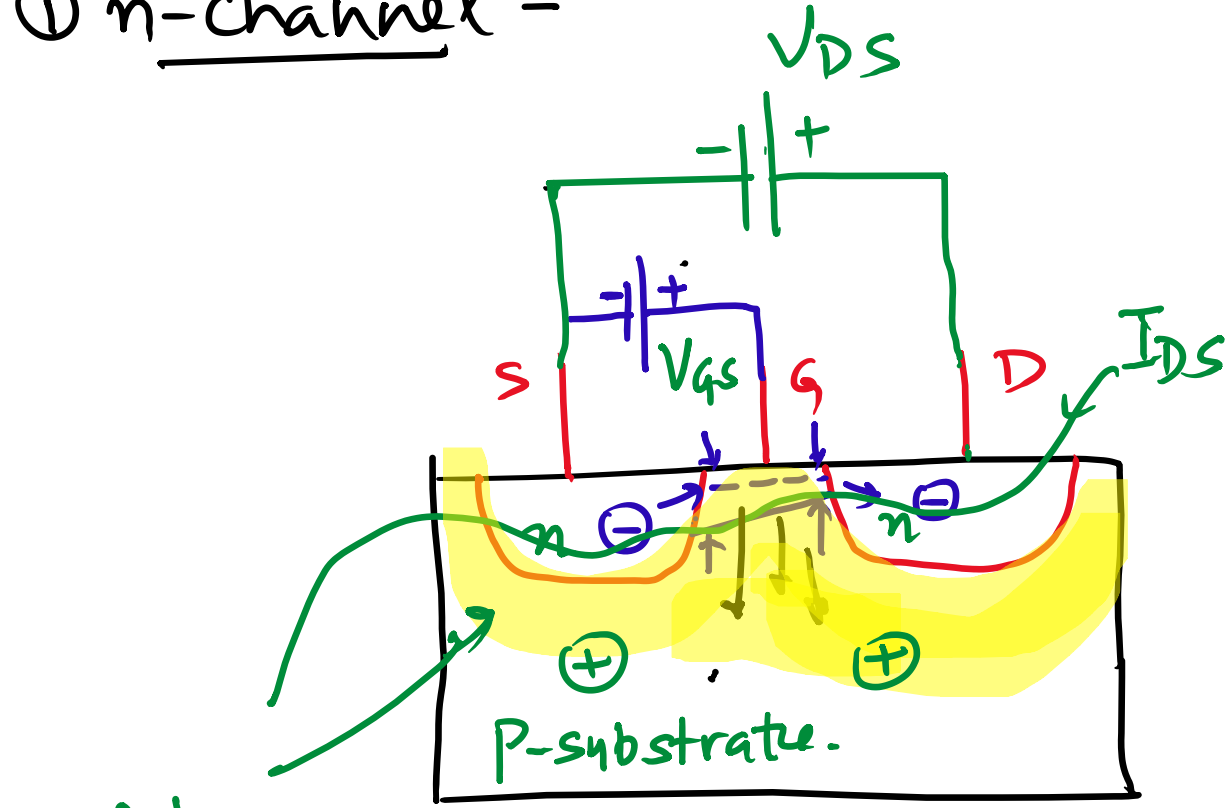


Q p-channel-D-type MOSFET



② Enhancement type MOSFET → (i) n-channel (ii) p-channel.

① n-channel -



Depletion region.

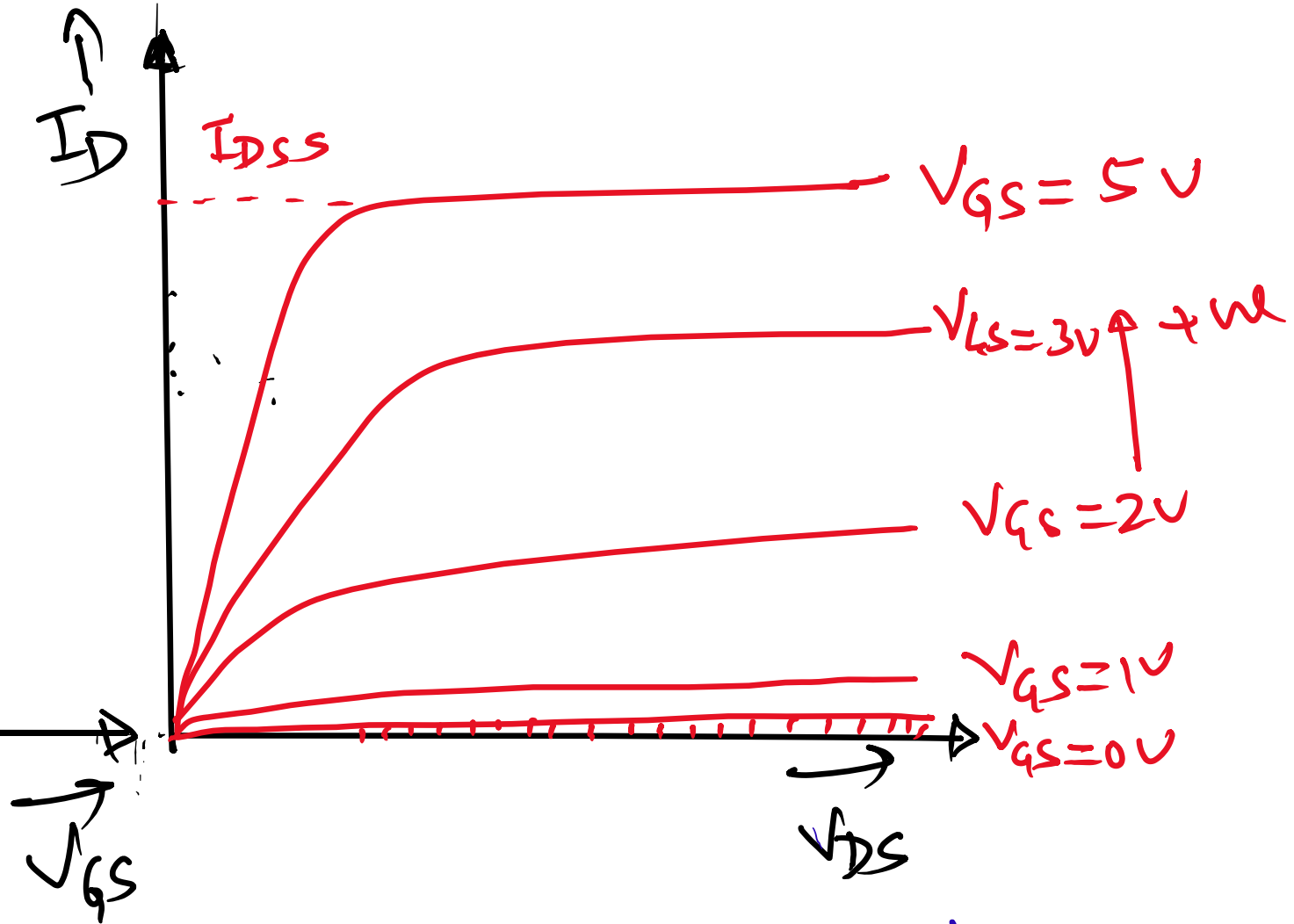
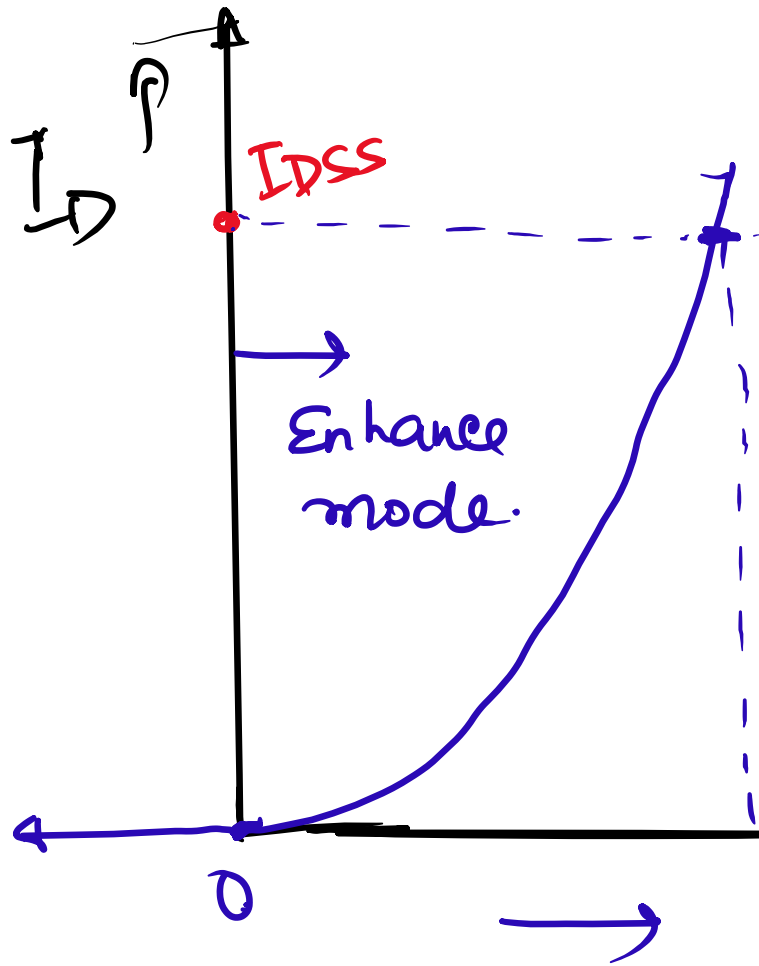
① $V_{GS} = 0V$

② $V_{GS} \Rightarrow +ve$, $V_{DS} \Rightarrow +ve$
→ channel is formed due to accumulation of e^- s near the gate terminal.

③ $V_{GS} \Rightarrow -ve$, V_{DS}

e^- of channel region will be repleled. and depletion region will be created.

Transfer characteristics -



JFET → { Fixed bias ✓
Self bias ✓
Potential divider bias ✓
Common gate. ✓
JFET ⇒ ($R_D = 0$) } - special cases.
 $V_{GSQ} = 0V$ ✓

Depletion type MOSFET ✓

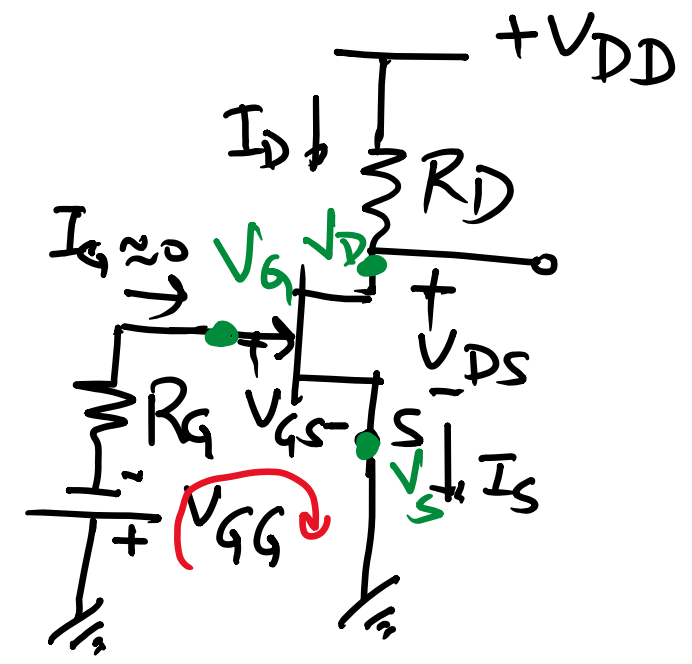
- ① Fixed bias ✓
- ② Potential divider bias ✓

Enhancement type -

- ① Feedback Configuration
- ② Potential divider bias

① Fixed bias (JFET) →

(Common Source Configuration)

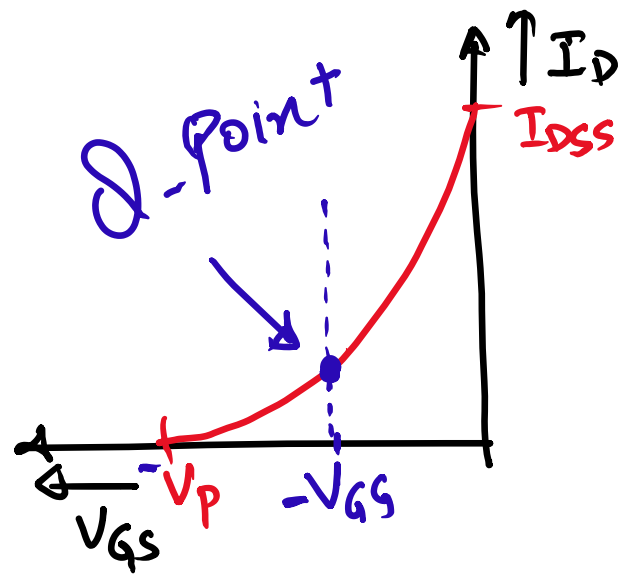


$$\textcircled{1} \quad \underline{I_G \approx 0} \Rightarrow \underline{I_D = I_S}$$

$$+V_{GG} + V_{GS} = 0 \Rightarrow \boxed{V_{GS} = -V_{GG}} \textcircled{1}$$

$$-V_{DD} + I_D R_D + V_{DS} = 0 \textcircled{2}$$

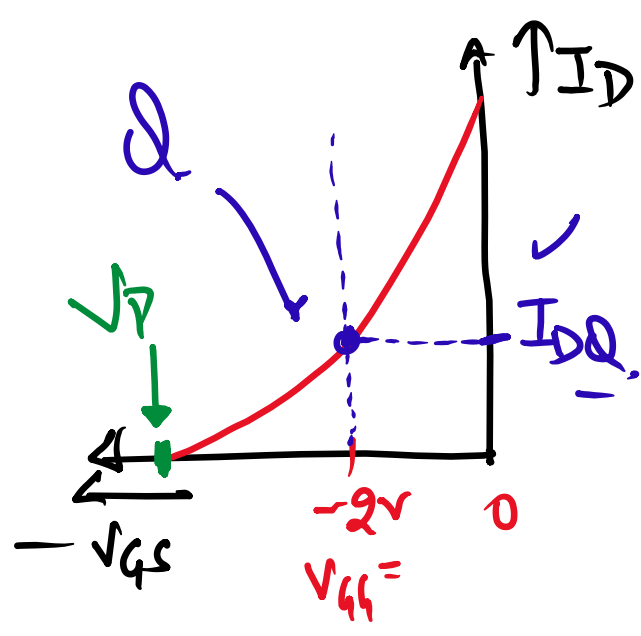
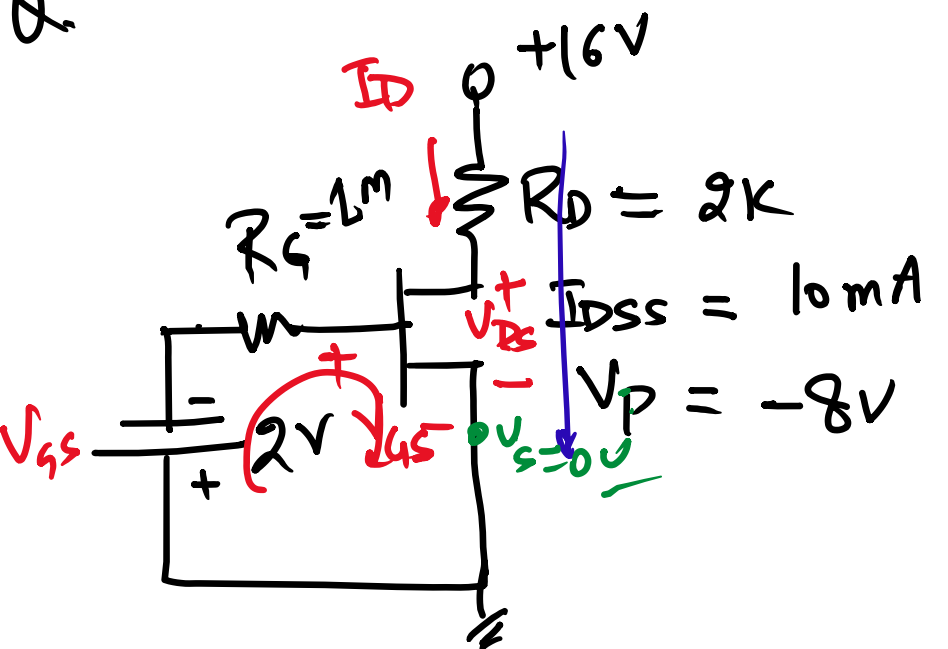
$$\boxed{V_{DS} = V_{DD} - I_D R_D}$$



$$\Rightarrow V_{DS} = V_D - V_S \Rightarrow V_S = 0 \text{ (F.B.)}$$

$$\Rightarrow \begin{matrix} V_{DS} = V_D \\ V_{GS} = V_G - V_S \Rightarrow \underline{\underline{V_{GS} = V_G}} \end{matrix}$$

Q



Determine -

V_{GSQ} , I_{DQ} , V_{DS} , V_D , V_G , V_S .

$I_G = 0 \Rightarrow I_D \approx I_S$

$+2 + V_{GS} = 0 \Rightarrow V_{GS} = -2V$

$I_D = I_{DSS} \left(1 - \frac{V_{GS}}{V_P}\right)^2 = 10 \times 10^{-3} \left(1 - \frac{-2}{-8}\right)^2$

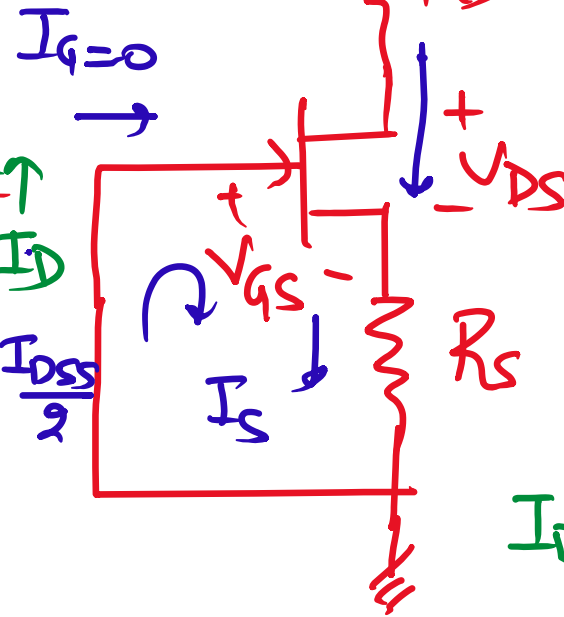
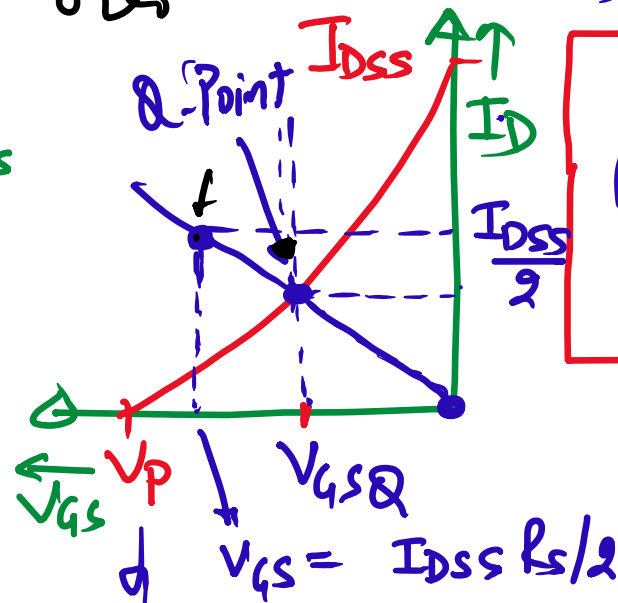
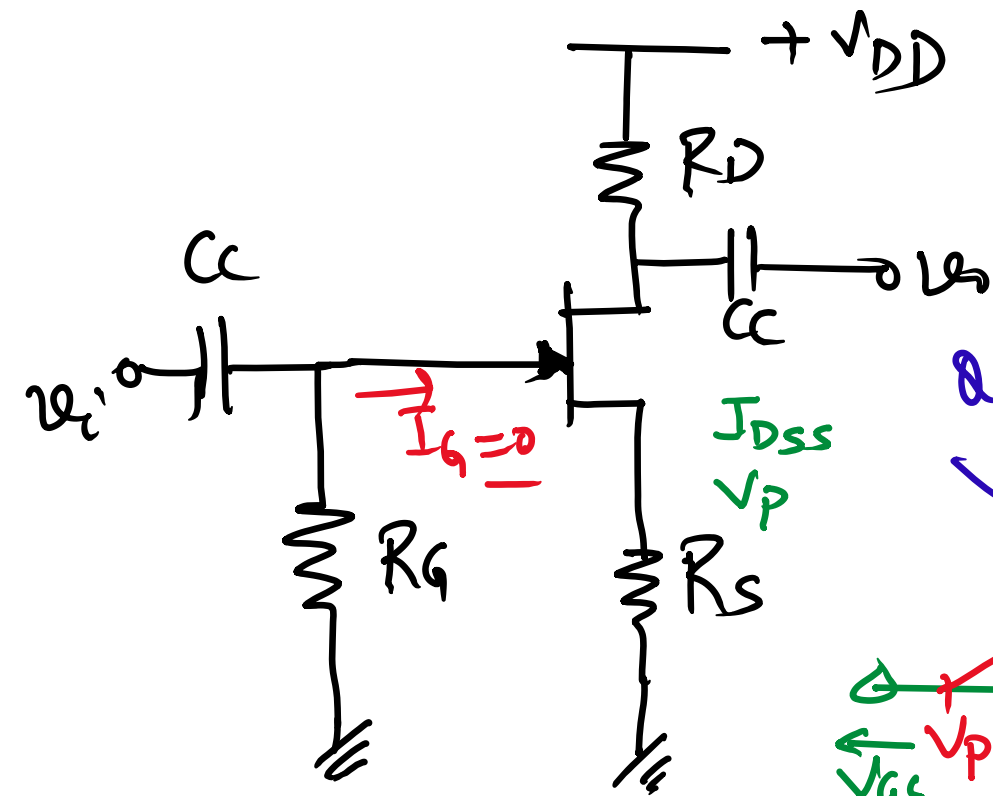
$-16 + I_D R_D + V_{DS} = 0$

$V_{DS} = V_D - V_S$, $V_{GS} = V_G - V_S$

$\rightarrow V_S = 0V$

② Self bias →

$I_G = 0$ ⇒ $I_D = I_S$



$V_{GS} + I_S R_S = 0$
 $V_{GS} = -I_D R_S$ ①

$I_D = I_{DSS} \left(1 - \frac{V_{GS}}{V_P}\right)^2$

$I_D = I_{DSS} \left(1 + \frac{I_D R_S}{V_P}\right)^2$

$I_D = \frac{1}{2} I_{DSS}$

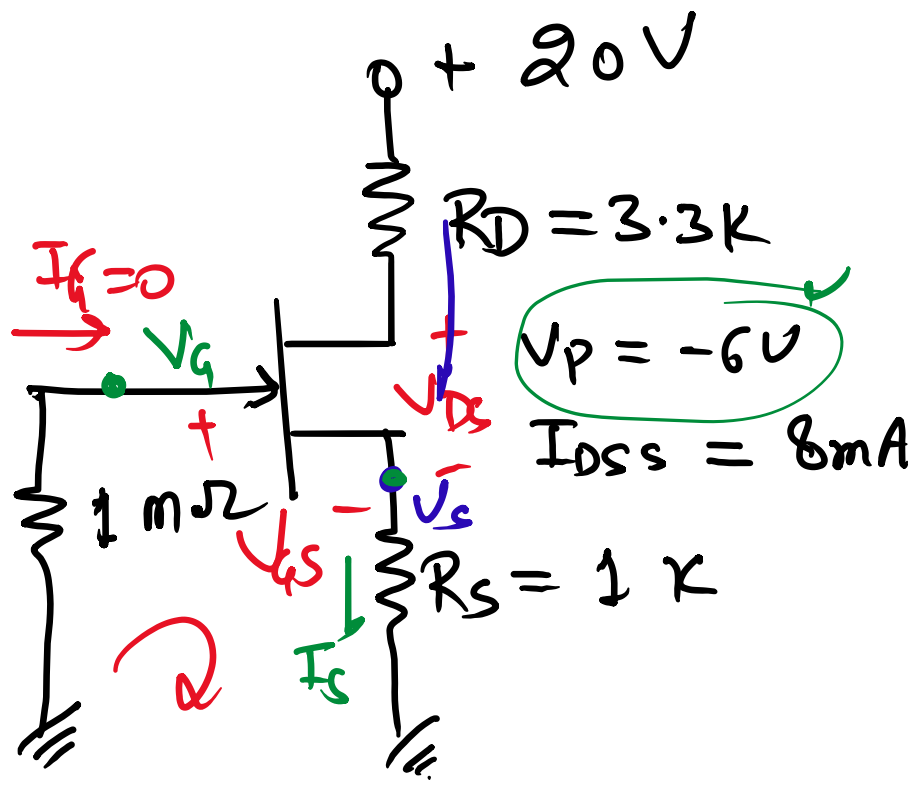
$-V_{DD} + I_D R_D + V_{DS} + I_D R_S = 0$

$V_{DS} = V_{DD} - I_D (R_D + R_S)$ ②

$I_D \approx \frac{I_{DSS}}{2}$

$V_{GS} = -\frac{I_{DSS} R_S}{2}$

Q.



$$I_D = I_{DSS} \left(\frac{V_{GS}}{V_p} \right)^2$$

$$V_{GS} = -I_D \cdot R_S$$

$$I_D = \frac{I_{DSS}}{2} \approx \frac{8}{2} = 4 \text{ mA}$$

$$V_{GS} = -4 \times 10^{-3} \times 10^{-3} = -4 \text{ V}$$

Determine - V_{GSQ} , I_{DQ} , V_{DS} , V_S , V_G

$$-20 + I_D \times 3.3 \times 10^3 + V_{DS} + 10^3 \times I_D = 0$$

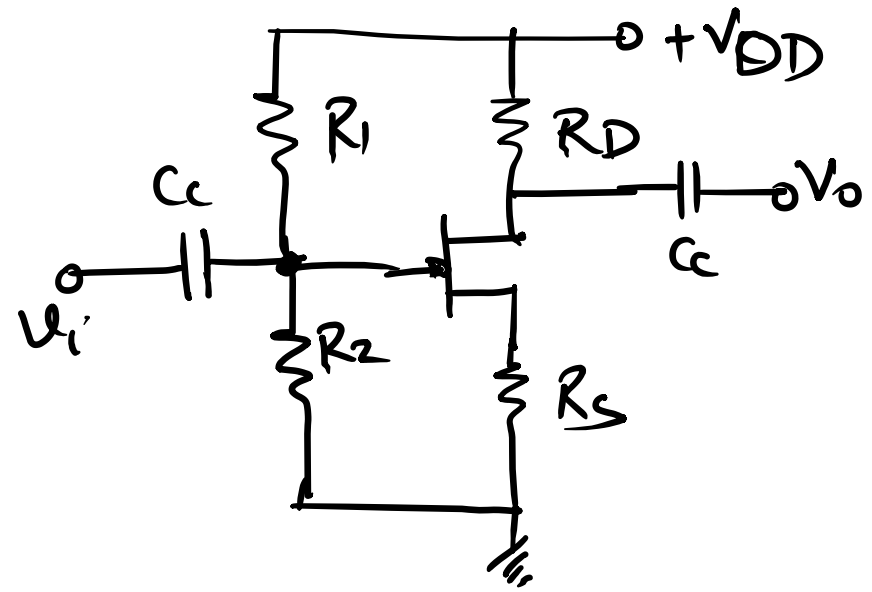
$$V_S = I_S R_S = I_D R_S$$

$$V_G = 0 \text{ V}$$

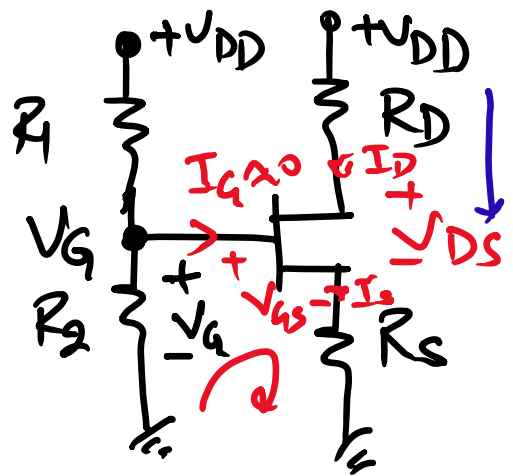
$$V_{DS} = V_D - V_S$$

③ Potential divider biasing (JFET) →

$I_G \approx 0 \Rightarrow I_D \approx I_S$



DC Analysis



Thevenin's theorem

$$V_G = + \frac{V_{DD} R_2}{R_1 + R_2}$$

$$-V_G + V_{GS} + I_D R_S = 0$$

$$V_{GS} = V_G - I_D R_S \quad \text{--- ①}$$

Conditions

$$-V_{DD} + I_D R_D + V_{DS} + I_D R_S = 0$$

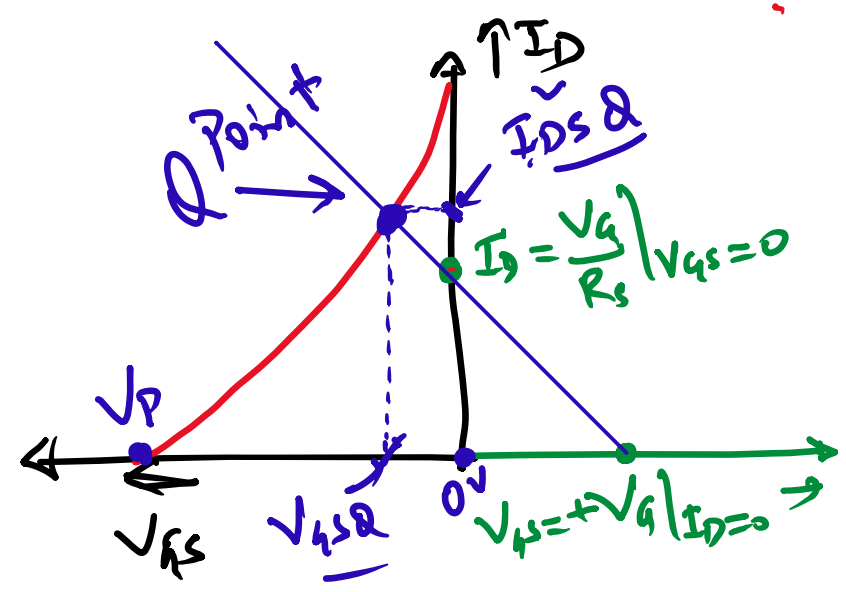
① $I_D = 0$

$$V_{GS} = +V_G$$

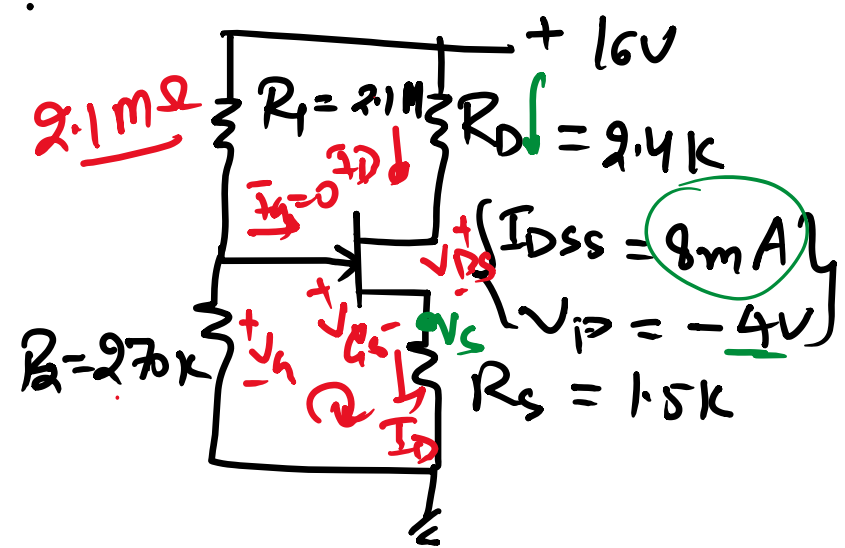
$$\neq \boxed{V_{DS} = V_{DD} - I_D (R_D + R_S)}$$

② $V_{GS} = 0$

$$0 = V_G - I_D R_S \Rightarrow I_D = \frac{V_G}{R_S}$$



Q Determine $\rightarrow \bar{I}_{DQ}, \bar{V}_D, V_{GSQ}, \bar{V}_S, \bar{V}_{DS}, \bar{V}_{DG}$

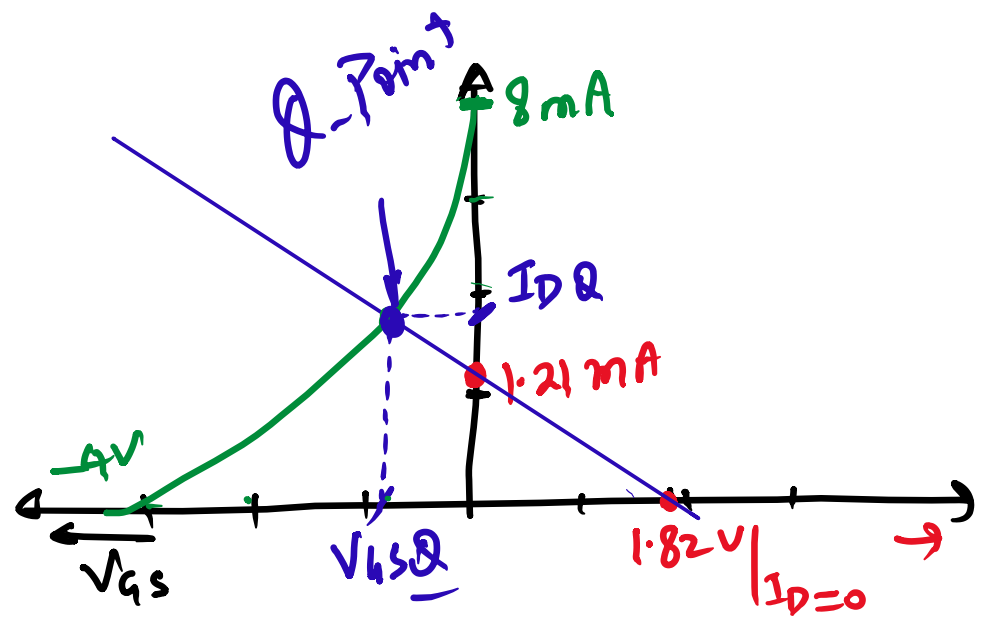


$$V_G = \frac{+V_{DD} R_2}{R_1 + R_2} = \underline{1.82V}$$

$$-V_G + V_{GS} + I_D R_S = 0 \Rightarrow \underline{V_{GS} = V_G - I_D R_S}$$

$$\textcircled{1} I_D = 0 \Rightarrow V_{GS} = \underline{V_G}$$

$$\textcircled{2} V_{GS} = 0 \Rightarrow I_D = V_G / R_S = \frac{1.82}{1.5 \times 10^3} = \underline{1.21 \text{ mA}}$$



$$\Rightarrow \left. \begin{aligned} I_{DQ} &= 2.4 \text{ mA} \\ V_{GSQ} &= -1.8 \text{ V} \end{aligned} \right\}$$

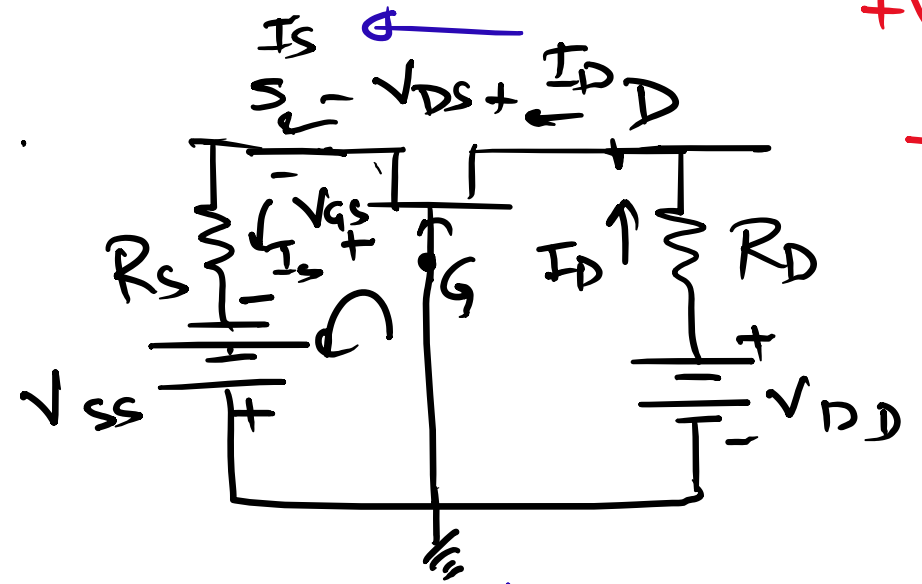
$$-V_{DD} + \bar{I}_D \bar{R}_D + V_{DS} + \bar{I}_D \bar{R}_S = 0 \Rightarrow \underline{V_{DS} = ?}$$

$$\bar{V}_{DS} = \bar{V}_D - \bar{V}_S \quad | \quad \bar{V}_{DG} = \bar{V}_D - \bar{V}_G$$

④ Common Gate Configuration -

$$I_S = 0 \Rightarrow \underline{I_D = I_S}$$

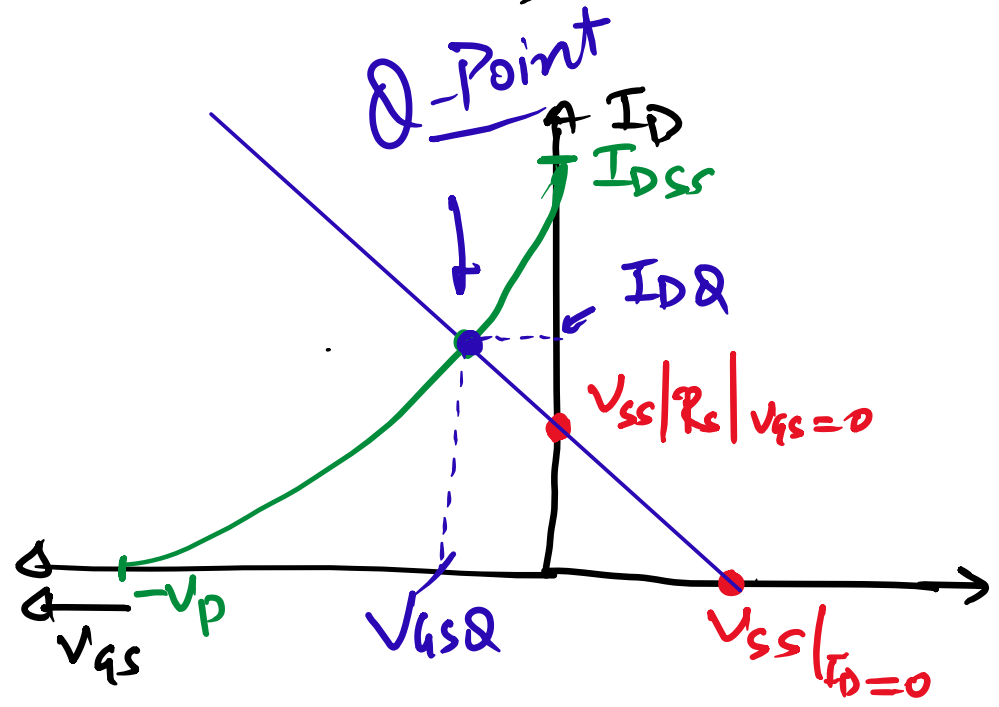
$$+V_{GS} + I_S R_S - V_{SS} = 0$$



$$\Rightarrow \boxed{V_{GS} = V_{SS} - I_D R_S} \quad \text{--- (1)}$$

- ① $I_D = 0 \Rightarrow V_{GS} = +V_{SS}$
- ② $V_{GS} = 0 \Rightarrow I_D = +V_{SS}/R_S$

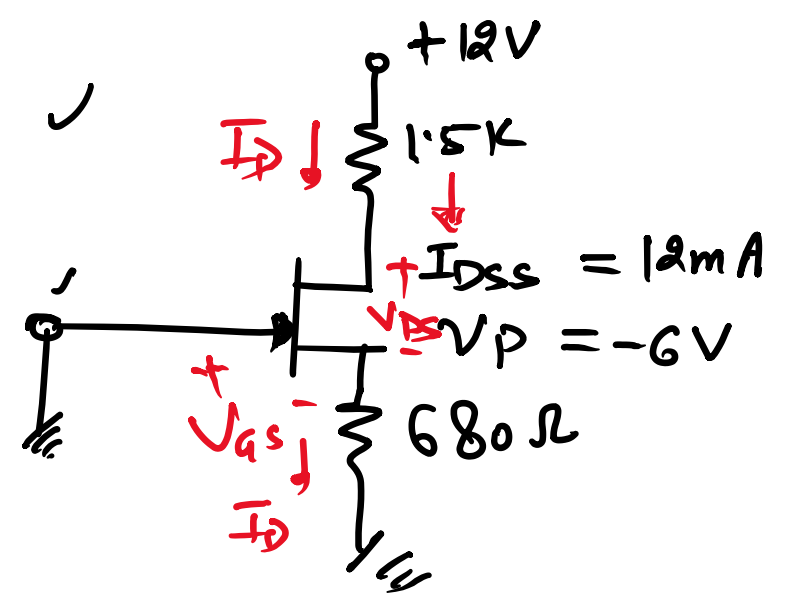
$\Rightarrow I_{DQ}, V_{GSQ} \leftarrow$ using graphical method.



$$-V_{DD} + I_D R_D + V_{DS} + I_D R_S - V_{SS} = 0 \Rightarrow \underline{V_{DS} = ?}$$

Q Determine $\rightarrow V_{GSQ}, I_{DQ}, V_D, V_G, V_S$ & V_{DS}

$I_G = 0 \Rightarrow I_D = I_S$



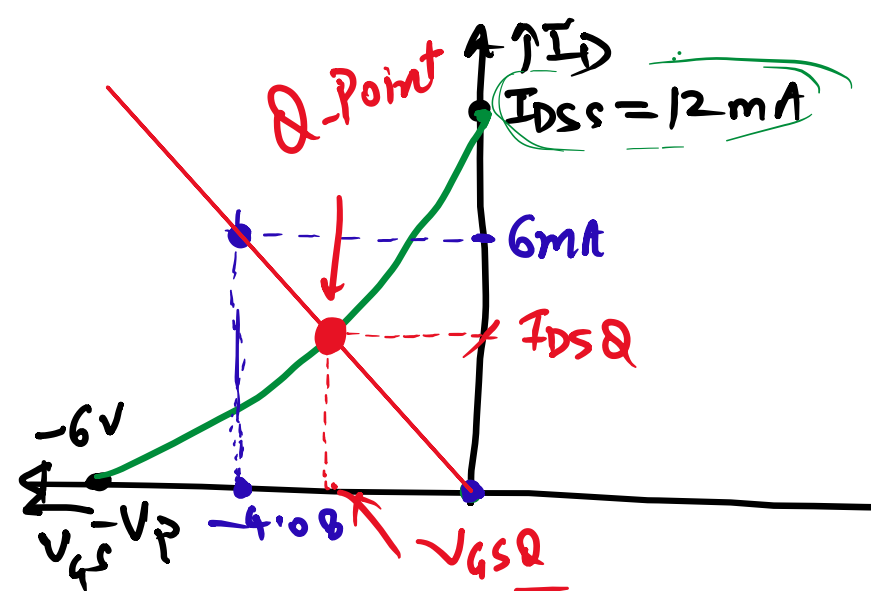
$\Rightarrow V_{GS} + I_D R_S = 0 \Rightarrow \underline{V_{GS} = -I_D R_S} \text{---(1)}$

- ① $I_D = 0 \Rightarrow \underline{V_{GS} = 0V}$
- ② $V_{GS} = 0 \Rightarrow \underline{I_D = 0}$

Assume any value of I_D
 $I_D = 6mA$
 $\left\{ \begin{array}{l} I_D \approx \frac{I_{DSS}}{2} \text{ or } \\ \frac{2 I_{DSS}}{4} \end{array} \right.$

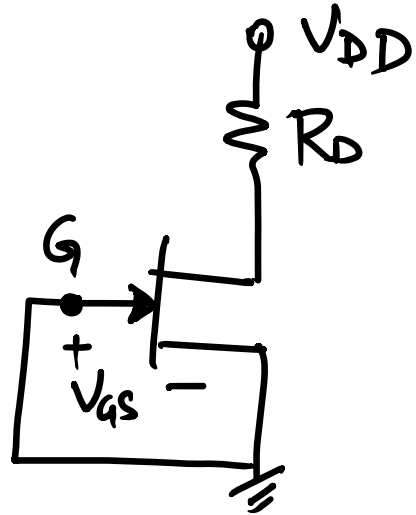
$V_{GS} = - 6 \times 680 \Omega \times 10^{-3} = \underline{-4.08V}$

$V_{GS} = -2.6V$ & $I_{DQ} = 3.8mA$

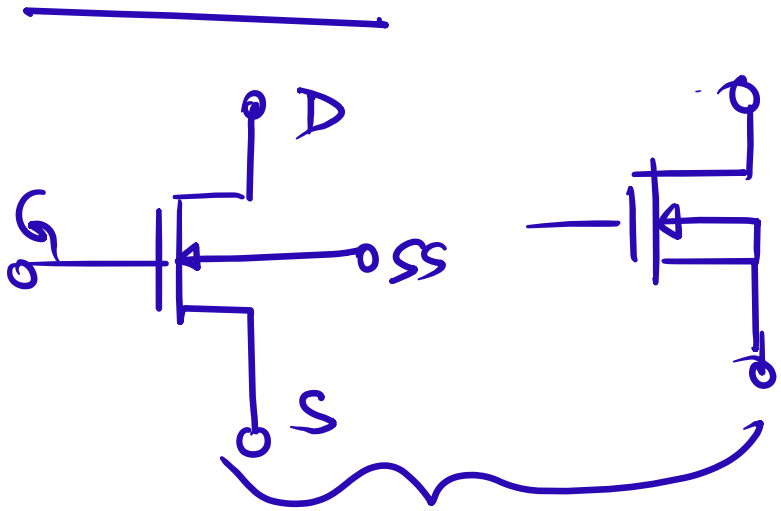


$-12 + 1.5 \times 10^3 \times I_D + V_{DS} + 680 \times I_D = 0 \Rightarrow V_{DS} = ?$
 $V_S = I_D R_S \Rightarrow V_{DS} = (V_D - V_S), \text{ \& } V_G = 0V$

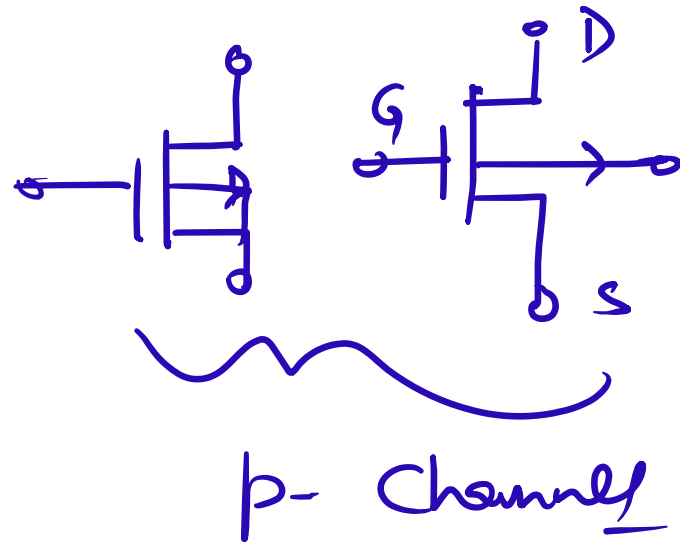
5) Special Cases - $V_{GSQ} = 0V$



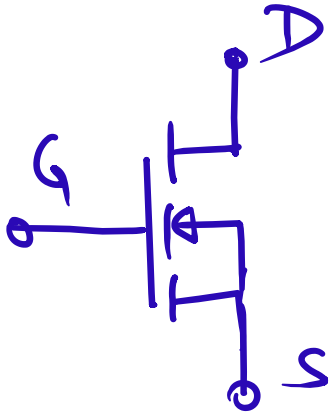
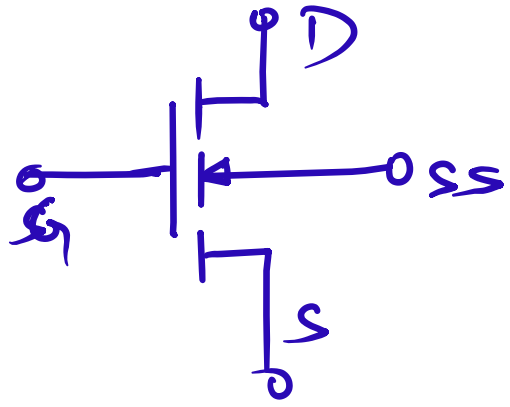
Study Special Cases.
A Depletion & Enhancement type MOSFET biasing.



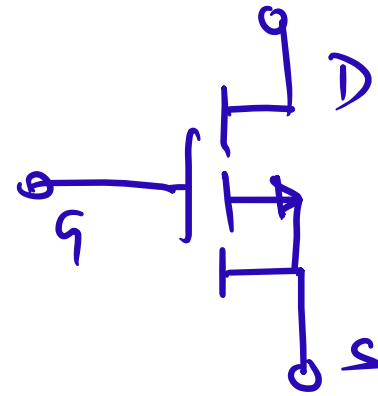
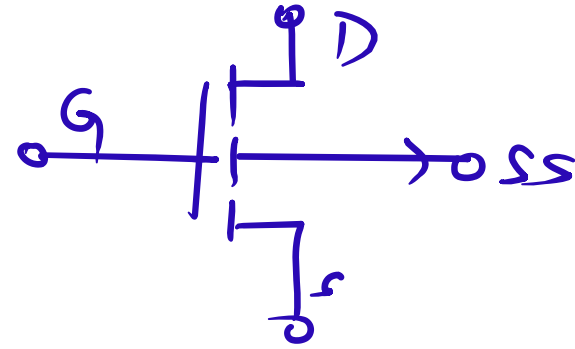
n-channel depletion type MOSFET



p-Channel



n-channel
Enhancement type
MOSFET



P-channel Enhancement
type MOSFET.

